

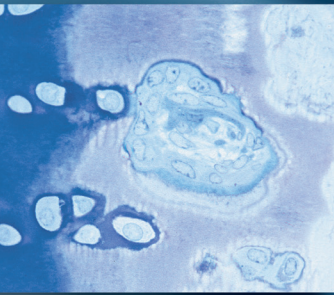
Volume 25, Number 1 February 2019

Microscopy AND Microanalysis



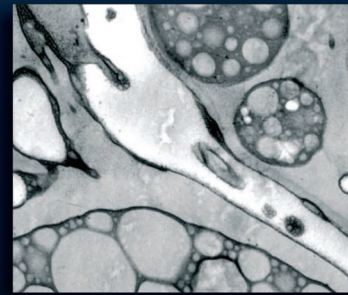
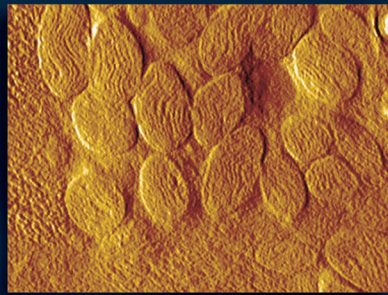
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An International Journal for the Biological and Physical Sciences

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Microscopy and Microanalysis is published bimonthly in February, April, June, August, October, and December by Cambridge University Press (1 Liberty Plaza, New York, NY 10006). Three supplements (*Meeting Guide*, *Program Guide*, and *Proceedings*) are published in June and August.

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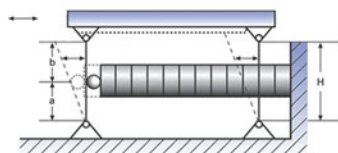
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